

**Notice of References Cited**

Application/Control No.

09/464,322

Applicant(s)/Patent Under  
Reexamination  
KWON ET AL.

Examiner

Chris C. Chu

Art Unit

2815

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

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